

Static @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	55			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.054		V/°C	Reference to 25°C, I _D = 1mA
R _{DS(on)}	Static Drain-to-Source On-Resistance		8.86	11	mΩ	V _{GS} = 10V, I _D = 37A ③
$V_{GS(th)}$	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}$, $I_D = 50\mu A$
gfs	Forward Trans conductance	120			S	$V_{DS} = 25V, I_{D} = 37A$ ③
I _{DSS}	Drain-to-Source Leakage Current			20		$V_{DS} = 55V, V_{GS} = 0V$
				250		$V_{DS} = 55V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
	Gate-to-Source Forward Leakage Gate-to-Source Reverse Leakage			200	A	V _{GS} = 20V
IGSS				-200	nA	$V_{GS} = -20V$

Dynamic Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

Q_g	Total Gate Charge	 40	60		I _D = 37A
Q_{gs}	Gate-to-Source Charge	 11		nC	$V_{DS} = 44V$
$\overline{Q_{gd}}$	Gate-to-Drain Charge	 15			V _{GS} = 10V③
$t_{d(on)}$	Turn-On Delay Time	 15			$V_{DD} = 28V$
t _r	Rise Time	 61			I _D = 37A
$t_{d(off)}$	Turn-Off Delay Time	 40		ns	$R_G = 12\Omega$
t _f	Fall Time	 35			V _{GS} = 10V③
L _D	Internal Drain Inductance	 4.5			Between lead, 6mm (0.25in.)
L _S	Internal Source Inductance	 7.5			from package and center of die contact
C _{iss}	Input Capacitance	 1720			$V_{GS} = 0V$
Coss	Output Capacitance	 290			$V_{DS} = 25V$
C _{rss}	Reverse Transfer Capacitance	 160		ъг	f = 1.0MHz
C _{oss}	Output Capacitance	 1000			$V_{GS} = 0V, V_{DS} = 1.0V f = 1.0MHz$
C _{oss}	Output Capacitance	 230			$V_{GS} = 0V, V_{DS} = 44V f = 1.0MHz$
Coss eff.	Effective Output Capacitance	 360			$V_{GS} = 0V, V_{DS} = 0V \text{ to } 44V $

Diode Characteristics

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	Parameter	Min.	Тур.	Max.	Units	Conditions
ı	Continuous Source Current			37		MOSFET symbol
I _S	(Body Diode)		31	_	showing the	
ı	Pulsed Source Current			_ 250		integral reverse
I _{SM} (Body Diode	(Body Diode) ①					p-n junction diode.
V_{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 37A, V_{GS} = 0V$ 3
t _{rr}	Reverse Recovery Time		20	40	ns	$T_J = 25^{\circ}C$, $I_F = 37A$, $V_{DD} = 28V$
Q _{rr}	Reverse Recovery Charge		14	28	nC	di/dt = 100A/µs ③
t _{on}	Forward Turn-On Time	Intrinsio	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)			

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- ② Limited by T_{Jmax} , starting $T_J = 25$ °C, L = 0.11mH, $R_G = 25\Omega$, $I_{AS} = 37$ A, $V_{GS} = 10$ V. Part not recommended for use above this value.
- \oplus C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}
- © Limited by T_{Jmax}, see Fig.12a, 12b, 15, 16 for typical repetitive avalanche performance.
- \odot This value determined from sample failure population, starting T_J = 25°C, L = 0.11mH, R_G = 25 Ω , I_{AS} = 37A, V_{GS} =10V.
- When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994
- ® R_{θ} is measured at T_{J} approximately 90°C.

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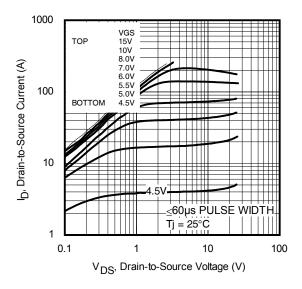


Fig. 1 Typical Output Characteristics

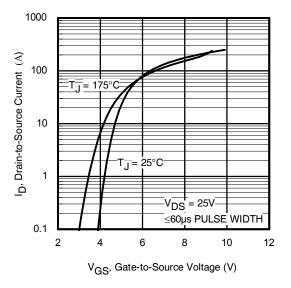


Fig. 3 Typical Transfer Characteristics

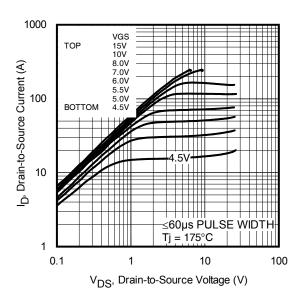


Fig. 2 Typical Output Characteristics

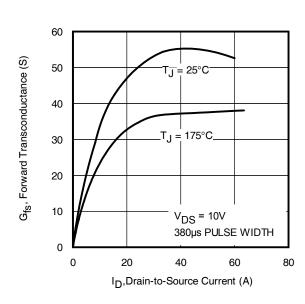


Fig. 4 Typical Forward Trans conductance Vs. Drain Current

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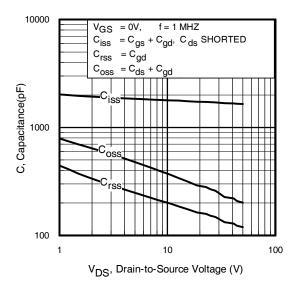


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

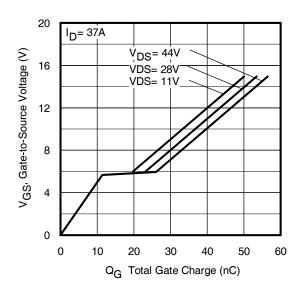


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

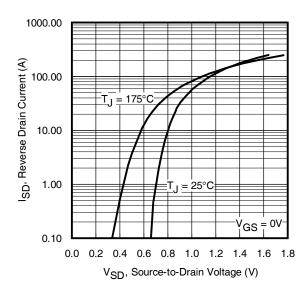


Fig. 7 Typical Source-to-Drain Diode Forward Voltage

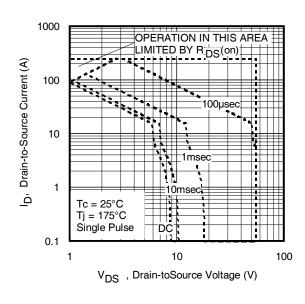
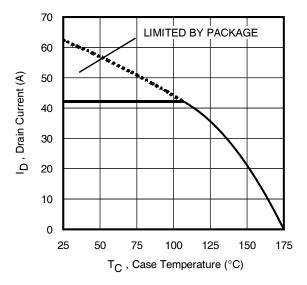


Fig 8. Maximum Safe Operating Area





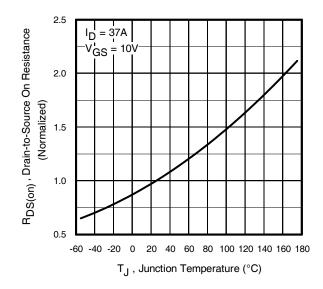


Fig 9. Maximum Drain Current Vs. Case Temperature

Fig 10. Normalized On-Resistance Vs. Temperature

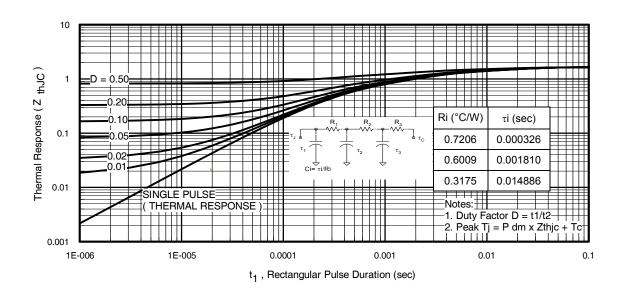


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

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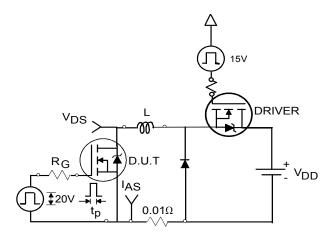


Fig 12a. Unclamped Inductive Test Circuit

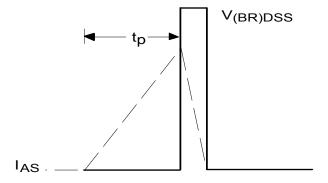


Fig 12b. Unclamped Inductive Waveforms

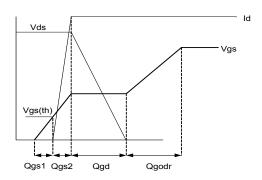


Fig 13a. Gate Charge Waveform

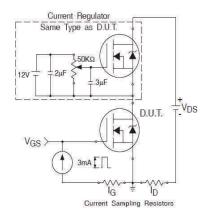


Fig 13b. Gate Charge Test Circuit

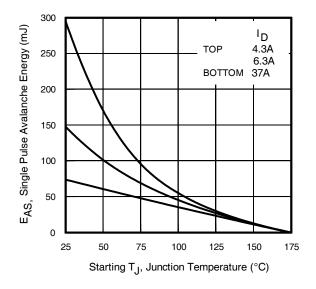


Fig 12c. Maximum Avalanche Energy vs. Drain Current

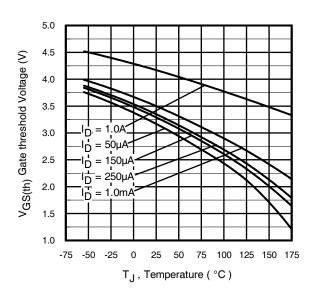


Fig 14. Threshold Voltage Vs. Temperature

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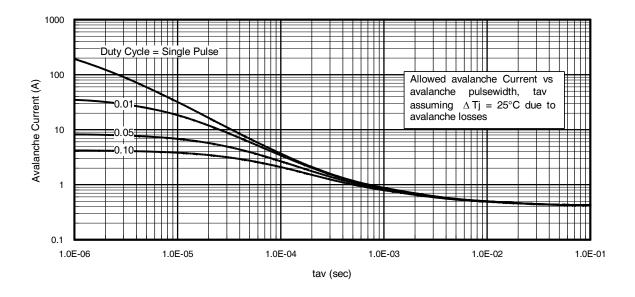


Fig 15. Typical Avalanche Current Vs. Pulse width

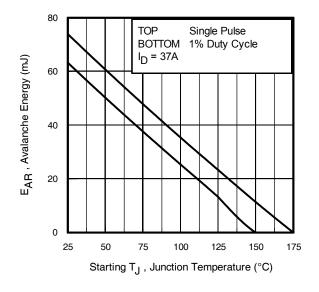


Fig 16. Maximum Avalanche Energy Vs. Temperature

Notes on Repetitive Avalanche Curves , Figures 15, 16:

(For further info, see AN-1005 at www.infineon.com)

- Avalanche failures assumption:
 Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{imax}. This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long as T_{jmax} is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
- 4. PD (ave) = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. lav = Allowable avalanche current.
- 7. ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 15, 16).

tav = Average time in avalanche.

D = Duty cycle in avalanche = tav ·f

ZthJC(D, tav) = Transient thermal resistance, see Figures 13)

$$\begin{split} P_{D \; (ave)} &= 1/2 \; (\; 1.3 \cdot BV \cdot I_{av}) = \Delta T / \; Z_{thJC} \\ I_{av} &= 2\Delta T / \; [1.3 \cdot BV \cdot Z_{th}] \\ E_{AS \; (AR)} &= P_{D \; (ave)} \cdot t_{av} \end{split}$$

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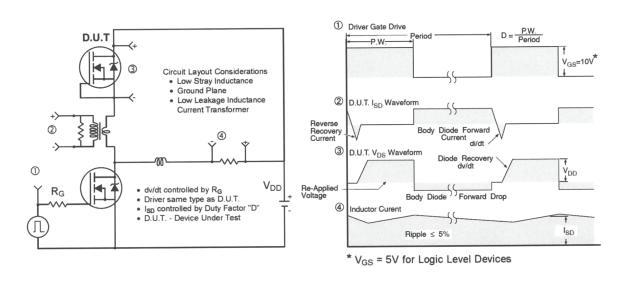


Fig 17. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

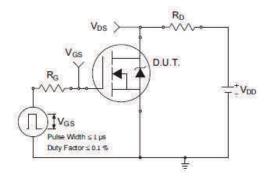


Fig 18a. Switching Time Test Circuit

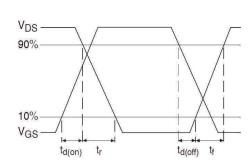
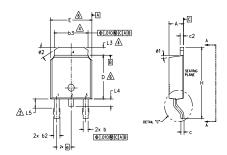


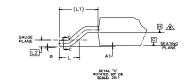
Fig 18b. Switching Time Waveforms

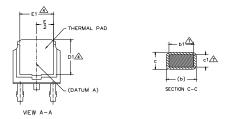


D-Pak (TO-252AA) Package Outline (Dimensions are shown in millimeters (inches))









NOTES:

- 1.- DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2.- DIMENSION ARE SHOWN IN INCHES [MILLIMETERS].
- 1 LEAD DIMENSION UNCONTROLLED IN L5.
- A- DIMENSION D1, E1, L3 & b3 ESTABLISH A MINIMUM MOUNTING SURFACE FOR THERMAL PAD.
- 5.- SECTION C-C DIMENSIONS APPLY TO THE FLAT SECTION OF THE LEAD BETWEEN .005 AND 0.10 [0.13 AND 0.25] FROM THE LEAD TIP.
- 6- DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED .005 [0.13] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
- A- DIMENSION b1 & c1 APPLIED TO BASE METAL ONLY.
- ♠ DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 9.- OUTLINE CONFORMS TO JEDEC OUTLINE TO-252AA.

S Y M	DIMENSIONS				
B	MILLIM	ETERS	INC	HES	O T E S
L	MIN.	MAX.	MIN.	MAX.	S
Α	2.18	2.39	.086	.094	
A1	-	0.13	-	.005	
b	0.64	0.89	.025	.035	
ь1	0.65	0.79	.025	.031	7
b2	0.76	1.14	.030	.045	
b3	4.95	5.46	.195	.215	4
С	0.46	0.61	.018	.024	
c1	0.41	0.56	.016	.022	7
c2	0.46	0.89	.018	.035	
D	5.97	6.22	.235	.245	6
D1	5.21	-	.205	-	4
Ε	6.35	6.73	.250	.265	6
E1	4.32	-	.170	-	4
е	2.29	BSC	.090	BSC	
Н	9.40	10.41	.370	.410	
L	1.40	1.78	.055	.070	
L1	2.74	BSC	.108	REF.	
L2	0.51	BSC	.020	BSC	
L3	0.89	1.27	.035	.050	4
L4	-	1.02	-	.040	
L5	1.14	1.52	.045	.060	3
ø	0,	10*	0,	10°	
ø1	0,	15*	0,	15*	
ø2	25*	35°	25*	35°	

LEAD ASSIGNMENTS

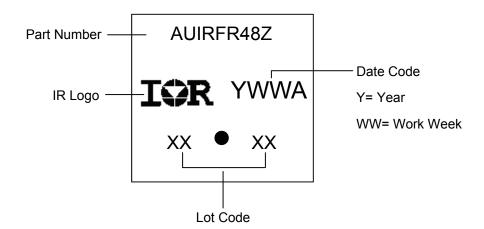
HEXFET

- 1.- GATE
- 2.- DRAIN
- 3.- SOURCE 4.- DRAIN

IGBT & CoPAK

- 1.- GATE
- 2.- COLLECTOR
- 3.- EMITTER
- 4.- COLLECTOR

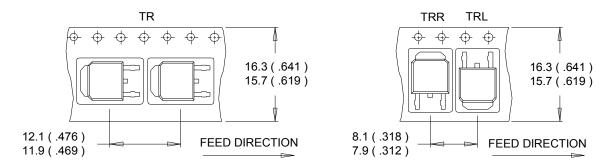
D-Pak (TO-252AA) Part Marking Information



Note: For the most current drawing please refer to IR website at http://www.irf.com/package/

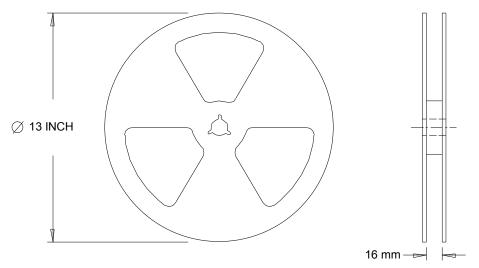


D-Pak (TO-252AA) Tape & Reel Information (Dimensions are shown in millimeters (inches))



NOTES:

- 1. CONTROLLING DIMENSION: MILLIMETER.
- 2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
- 3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES:

1. OUTLINE CONFORMS TO EIA-481.

Note: For the most current drawing please refer to IR website at http://www.irf.com/package/

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Qualification Information

			Automotive			
		(per AEC-Q101)				
		Comments: This part number(s) passed Automotive qualification. Infineon's Industrial and Consumer qualification level is granted by extension of the higher Automotive level.				
Moisture	Sensitivity Level	D-Pak MSL1				
	Machine Madel	Class M4 (+/-425V) [†]				
	Machine Model	AEC-Q101-002				
FOD	Lluman Dady Madal	Class H1B (+/-1000V) [†]				
ESD	Human Body Model	AEC-Q101-001				
	Charred Davis Madel	Class C5 (+/-1125V) [†]				
	Charged Device Model	AEC-Q101-005				
RoHS Compliant		Yes				

[†] Highest passing voltage.

Revision History

Date	Comments			
12/1/2015	Updated datasheet with corporate template			
12/1/2013	Corrected ordering table on page 1.			

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